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- ☐ 1. The Noaa Geosat Program: Monitoring Tropical Sea Level With Satellite A
Cheney, R.; Douglas, B.; Miller, L.; Agreen, R.; Doyle, N.;
Geoscience and Remote Sensing Symposium, 1989. IGARSS'89. 12th Canadi
on Remote Sensing. 1989 International
Volume 2, July 10 -14th 1989 Page(s):1053 - 1053
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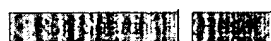
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<phrase> ((group <or> set <or> assortment
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several) <phrase> (sample <or> wafer <or>
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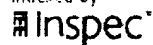
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- ☐ 1. **Experimental characterization of resistive joints for use inside ATLAS tor**
Volpini, G.; Baccaglioni, G.; Pojer, M.;
Applied Superconductivity, IEEE Transactions on
Volume 11, Issue 1, Part 2, March 2001 Page(s):2130 - 2133
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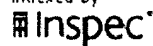
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plural <or> numerous) <phrase> (wafers
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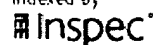
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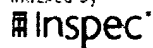
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Wells, C.H.; Larson, R.E.;
Proceedings of the IEEE
Volume 58, Issue 1, Jan. 1970 Page(s):16 - 22
[AbstractPlus](#) | Full Text: [PDF\(596 KB\)](#) IEEE JNL
- ☐ 2. **Sufficient conditions for hyperstability of a class of nonlinear systems**
Chang Han;
Automatic Control, IEEE Transactions on
Volume 15, Issue 6, Dec 1970 Page(s):705 - 706
[AbstractPlus](#) | Full Text: [PDF\(304 KB\)](#) IEEE JNL
- ☐ 3. **Stabilized suboptimal periodic control of a chemical reactor**
Matsubara, M.; Onogi, K.;
Automatic Control, IEEE Transactions on
Volume 23, Issue 6, Dec 1978 Page(s):1005 - 1008
[AbstractPlus](#) | Full Text: [PDF\(392 KB\)](#) IEEE JNL
- ☐ 4. **Filtering in nonlinear time delay systems**
Yu, T.; Seinfeld, J.; Ray, W.;
Automatic Control, IEEE Transactions on
Volume 19, Issue 4, Aug 1974 Page(s):324 - 333
[AbstractPlus](#) | Full Text: [PDF\(840 KB\)](#) IEEE JNL
- ☐ 5. **Modern Wiener-Hopf design of optimal controllers--Part II: The multivaria**
Youla, D.; Jabr, H.; Bongiorno, J., Jr.;
Automatic Control, IEEE Transactions on
Volume 21, Issue 3, Jun 1976 Page(s):319 - 338
[AbstractPlus](#) | Full Text: [PDF\(1544 KB\)](#) IEEE JNL
- ☐ 6. **Unstable suboptimal periodic control of a certain chemical reactor**
Matsubara, M.; Onogi, K.;
Automatic Control, IEEE Transactions on
Volume 23, Issue 6, Dec 1978 Page(s):1111 - 1113
[AbstractPlus](#) | Full Text: [PDF\(312 KB\)](#) IEEE JNL

- 7. **Application of higher order bifurcation formulas**
Colantoni, M.C.; Padin, M.; Desages, A.; Romagnoli, J.A.;
Automatic Control, IEEE Transactions on
Volume 36, Issue 6, June 1991 Page(s):746 - 749
Digital Object Identifier 10.1109/9.86949
[AbstractPlus](#) | Full Text: [PDF](#)(340 KB) IEEE JNL

- 8. **Computing bifurcation points via characteristics gain loci**
Moiola, J.; Desages, A.; Romagnoli, J.;
Automatic Control, IEEE Transactions on
Volume 36, Issue 3, March 1991 Page(s):358 - 362
Digital Object Identifier 10.1109/9.73571
[AbstractPlus](#) | Full Text: [PDF](#)(348 KB) IEEE JNL

- 9. **The successive approximation procedure for finite-time optimal control o systems**
Aganovic, Z.; Gajic, Z.;
Automatic Control, IEEE Transactions on
Volume 39, Issue 9, Sept. 1994 Page(s):1932 - 1935
Digital Object Identifier 10.1109/9.317128
[AbstractPlus](#) | Full Text: [PDF](#)(304 KB) IEEE JNL

- 10. **SVD-NET: an algorithm that automatically selects network structure**
Psichogios, D.C.; Ungar, L.H.;
Neural Networks, IEEE Transactions on
Volume 5, Issue 3, May 1994 Page(s):513 - 515
Digital Object Identifier 10.1109/72.286929
[AbstractPlus](#) | Full Text: [PDF](#)(296 KB) IEEE JNL

- 11. **Dynamic process monitoring and fault diagnosis with qualitative models**
Vinson, J.M.; Ungar, L.H.;
Systems, Man and Cybernetics, IEEE Transactions on
Volume 25, Issue 1, Jan. 1995 Page(s):181 - 189
Digital Object Identifier 10.1109/21.362954
[AbstractPlus](#) | Full Text: [PDF](#)(844 KB) IEEE JNL

- 12. **Robust feedback stabilization of chemical reactors**
Viel, F.; Jadot, F.; Bastin, G.;
Automatic Control, IEEE Transactions on
Volume 42, Issue 4, April 1997 Page(s):473 - 481
Digital Object Identifier 10.1109/9.566657
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(388 KB) IEEE JNL


- 13. **An algebraic criterion for robust stability of linear control systems**
Dainson, B.E.; Lewin, D.R.;
Automatic Control, IEEE Transactions on
Volume 43, Issue 2, Feb. 1998 Page(s):237 - 241
Digital Object Identifier 10.1109/9.661073
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(180 KB) IEEE JNL

- 14. **Predictive control of a bench-scale chemical reactor based on neural-net**
Schenker, B.; Agarwal, M.;
Control Systems Technology, IEEE Transactions on
Volume 6, Issue 3, May 1998 Page(s):388 - 400
Digital Object Identifier 10.1109/87.668039
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(276 KB) IEEE JNL

- 15. **Investigation of high-temperature degradation of platinum thin films with**

- resistance measurement apparatus
Firebaugh, S.L.; Jensen, K.F.; Schmidt, M.A.;
Microelectromechanical Systems, Journal of
Volume 7, Issue 1, March 1998 Page(s):128 - 135
Digital Object Identifier 10.1109/84.661395
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(232 KB) IEEE JNL
16. Plasma-assisted chemical process for NO_x control
Yamamoto, T.; Yang, C.-L.; Beltran, M.R.; Kravets, Z.;
Industry Applications, IEEE Transactions on
Volume 36, Issue 3, May-June 2000 Page(s):923 - 927
Digital Object Identifier 10.1109/28.845073
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(128 KB) IEEE JNL
17. Miniaturization and integration of photoacoustic detection with a microfa chemical reactor system
Firebaugh, S.L.; Jensen, K.F.; Schmidt, M.A.;
Microelectromechanical Systems, Journal of
Volume 10, Issue 2, June 2001 Page(s):232 - 237
Digital Object Identifier 10.1109/84.925756
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(144 KB) IEEE JNL
18. Fabrication of air-channel structures for microfluidic, microelectromecha microelectronic applications
Bhusari, D.; Reed, H.A.; Wedlake, M.; Padovani, A.M.; Allen, S.A.B.; Kohl, P.A
Microelectromechanical Systems, Journal of
Volume 10, Issue 3, Sept. 2001 Page(s):400 - 408
Digital Object Identifier 10.1109/84.946793
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(216 KB) IEEE JNL
19. Towards ideal NO_x control technology using a plasma-chemical hybrid p
Yamamoto, T.; Okubo, M.; Hayakawa, K.; Kitaura, K.;
Industry Applications, IEEE Transactions on
Volume 37, Issue 5, Sept.-Oct. 2001 Page(s):1492 - 1498
Digital Object Identifier 10.1109/28.952526
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(160 KB) IEEE JNL
20. Application of iterative learning control to an exothermic semibatch chen
Mezghani, M.; Roux, G.; Cabassud, M.; Le Lann, M.V.; Dahhou, B.; Casamatt
Control Systems Technology, IEEE Transactions on
Volume 10, Issue 6, Nov. 2002 Page(s):822 - 834
Digital Object Identifier 10.1109/TCST.2002.804117
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(582 KB) IEEE JNL
21. Simultaneous removal of NO/sub x/, SO/sub x/, and CO/sub 2/ at elevattec using a plasma-chemical hybrid process
Yamamoto, T.; Okubo, M.; Nagaoka, T.; Hayakawa, K.;
Industry Applications, IEEE Transactions on
Volume 38, Issue 5, Sept.-Oct. 2002 Page(s):1168 - 1173
Digital Object Identifier 10.1109/TIA.2002.802911
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(260 KB) IEEE JNL
22. Pattern matching in historical batch data using PCA
Singhal, A.; Seborg, D.E.;
Control Systems Magazine, IEEE
Volume 22, Issue 5, Oct. 2002 Page(s):53 - 63
Digital Object Identifier 10.1109/MCS.2002.1035217
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(787 KB) IEEE JNL

23. **A microfabricated suspended-tube chemical reactor for thermally efficient processing**
Arana, L.R.; Schaevitz, S.B.; Franz, A.J.; Schmidt, M.A.; Jensen, K.F.;
Microelectromechanical Systems, Journal of
Volume 12, Issue 5, Oct. 2003 Page(s):600 - 612
Digital Object Identifier 10.1109/JMEMS.2003.817897
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(1225 KB) IEEE JNL
24. **Sliding-mode control scheme for a class of continuous chemical reactors**
Aguilar-Lopez, R.; Alvarez-Ramirez, J.;
Control Theory and Applications, IEE Proceedings-
Volume 149, Issue 4, July 2002 Page(s):263 - 268
Digital Object Identifier 10.1049/ip-cta:20020558
[AbstractPlus](#) | Full Text: [PDF](#)(450 KB) IEEE JNL
25. **Robust linearising controllers for nonlinear time-delay systems**
Wu, W.;
Control Theory and Applications, IEE Proceedings-
Volume 146, Issue 1, Jan. 1999 Page(s):91 - 97
Digital Object Identifier 10.1049/ip-cta:19990377
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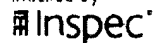
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 Polla, D.L.; Muller, R.S.; White, R.M.;
 Electron Device Letters, IEEE
 Volume 7, Issue 4, Apr 1986 Page(s):254 - 256
[AbstractPlus](#) | Full Text: [PDF](#)(408 KB) IEEE JNL
- ☐ 2. **Design criteria for uniform reaction rates in an oxygen plasma**
 Batley, J.F.;
 Electron Devices, IEEE Transactions on
 Volume 24, Issue 2, Feb 1977 Page(s):140 - 146
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- ☐ 3. **WP-B2 chemical reaction monitoring with the charge-flow transistor**
 Sheppard, N.F.; Appelman, H.R.; Poh, S.Y.; Senturia, S.D.;
 Electron Devices, IEEE Transactions on
 Volume 27, Issue 11, Nov 1980 Page(s):2201 - 2201
[AbstractPlus](#) | Full Text: [PDF](#)(176 KB) IEEE JNL
- ☐ 4. **Reactive ion etching for VLSI**
 Ephrath, L.M.;
 Electron Devices, IEEE Transactions on
 Volume 28, Issue 11, Nov 1981 Page(s):1315 - 1319
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- ☐ 5. **Process Modeling for Photoresist Development and Design of DLR/sd (Direct Resist by a Single Development) Process**
 Hirai, Y.; Sasago, M.; Masayuki Endo; Tsuji, K.; Mano, Y.;
 Computer-Aided Design of Integrated Circuits and Systems, IEEE Transaction:
 Volume 6, Issue 3, May 1987 Page(s):403 - 409
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- ☐ 6. **The Chemistry of Failure of Aluminum Electrolytic Capacitors**
 Alwitt, R.; Hills, R.;
 Parts, Materials and Packaging, IEEE Transactions on
 Volume 1, Issue 2, Sep 1965 Page(s):28 - 34
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- ☐ 7. **The Lubrication of Sliding Base Metal Contacts**
Campbell, W.; Thomas, U., Jr.;
Parts, Hybrids, and Packaging, IEEE Transactions on
Volume 12, Issue 2, Jun 1976 Page(s):147 - 153
[AbstractPlus](#) | Full Text: [PDF\(1040 KB\)](#) IEEE JNL

- ☐ 8. **Chemical reaction networks**
Oster, G.; Perelson, A.;
Circuits and Systems, IEEE Transactions on
Volume 21, Issue 6, Nov 1974 Page(s):709 - 721
[AbstractPlus](#) | Full Text: [PDF\(1304 KB\)](#) IEEE JNL

- ☐ 9. **Material Characterization of Thick Film Resistor Pastes**
Shah, J.; Hahn, W.;
Components, Hybrids, and Manufacturing Technology, IEEE Transactions on [Trans. on Components, Packaging, and Manufacturing Technology, Part A, B,
Volume 1, Issue 4, Dec 1978 Page(s):383 - 392
[AbstractPlus](#) | Full Text: [PDF\(1824 KB\)](#) IEEE JNL

- ☐ 10. **Applications of nonelementary catastrophe theory**
Stewart, I.;
Circuits and Systems, IEEE Transactions on
Volume 31, Issue 2, Feb 1984 Page(s):165 - 174
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- ☐ 11. **Gamma-ray radiation effects on hydroxyl absorption increase in optical f**
Itoh, H.; Ohmori, Y.; Nakahara, M.;
Lightwave Technology, Journal of
Volume 4, Issue 4, Apr 1986 Page(s):473 - 477
[AbstractPlus](#) | Full Text: [PDF\(632 KB\)](#) IEEE JNL

- ☐ 12. **Loss increases due to chemical reactions of hydrogen in silica glass opt**
Itoh, H.; Ohmori, Y.; Nakahara, M.;
Lightwave Technology, Journal of
Volume 3, Issue 5, Oct 1985 Page(s):1100 - 1104
[AbstractPlus](#) | Full Text: [PDF\(568 KB\)](#) IEEE JNL

- ☐ 13. **Infrared optical loss increase in silica fibers due to hydrogen**
Uchida, N.; Uesugi, N.;
Lightwave Technology, Journal of
Volume 4, Issue 8, Aug 1986 Page(s):1132 - 1138
[AbstractPlus](#) | Full Text: [PDF\(736 KB\)](#) IEEE JNL

- ☐ 14. **Reaction property of diffused H₂ with defect Centers in GeO₂-doped fiber**
Itoh, H.; Shimizu, M.; Ohmori, Y.; Nakahara, M.;
Lightwave Technology, Journal of
Volume 5, Issue 1, Jan 1987 Page(s):134 - 139
[AbstractPlus](#) | Full Text: [PDF\(1888 KB\)](#) IEEE JNL

- ☐ 15. **Infrared loss increase phenomenon of coated optical fibers at high temp**
Uesugi, N.; Kuwabara, T.; Ishida, Y.; Noguchi, K.; Negishi, Y.; Uchida, N.;
Lightwave Technology, Journal of
Volume 3, Issue 4, Aug 1985 Page(s):824 - 828
[AbstractPlus](#) | Full Text: [PDF\(688 KB\)](#) IEEE JNL

- ☐ 16. **Research needs in magnetic separation**

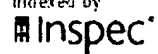
- Kolm, H.;
Magnetics, IEEE Transactions on
Volume 12, Issue 5, Sep 1976 Page(s):450 - 454
[AbstractPlus](#) | Full Text: [PDF](#)(640 KB) IEEE JNL
17. **A topotactic technique for the production of mechanically oriented plana**
Licci, F.; Asti, G.;
Magnetics, IEEE Transactions on
Volume 15, Issue 6, Nov 1979 Page(s):1867 - 1869
[AbstractPlus](#) | Full Text: [PDF](#)(208 KB) IEEE JNL
18. **Aging of magnetic recording tape**
Cuddihy, E.;
Magnetics, IEEE Transactions on
Volume 16, Issue 4, Jul 1980 Page(s):558 - 568
[AbstractPlus](#) | Full Text: [PDF](#)(1072 KB) IEEE JNL
19. **Coercivity reduction in thin orthoferrite plates by annealing**
Heinlein, E.; Pierce, R.;
Magnetics, IEEE Transactions on
Volume 6, Issue 3, Sep 1970 Page(s):493 - 496
[AbstractPlus](#) | Full Text: [PDF](#)(656 KB) IEEE JNL
20. **Microwave-Induced Hyperthermia Dose Definition**
Atkinson, E.R.;
Microwave Theory and Techniques, IEEE Transactions on
Volume 26, Issue 8, Aug 1978 Page(s):595 - 598
[AbstractPlus](#) | Full Text: [PDF](#)(416 KB) IEEE JNL
21. **Microwave Processing and Diagnosis of Chemically Reacting Materials in Cavity Applicator**
Jow, J.; Hawley, M.C.; Finzel, M., Jr.; Asmussen, J.; Haw-Hwa Lin; Maring, B.;
Microwave Theory and Techniques, IEEE Transactions on
Volume 35, Issue 12, Dec 1987 Page(s):1435 - 1443
[AbstractPlus](#) | Full Text: [PDF](#)(1192 KB) IEEE JNL
22. **Initiation of NF₃-H₂chemical reactions via CO₂laser irradiation of NF₄BF₄**
Benson, R.; Bowen, R.; Dengel, O.;
Quantum Electronics, IEEE Journal of
Volume 16, Issue 11, Nov 1980 Page(s):1223 - 1226
[AbstractPlus](#) | Full Text: [PDF](#)(1352 KB) IEEE JNL
23. **Introduction to section III--Chemical reactions initiated by lasers**
Jensen, R.;
Quantum Electronics, IEEE Journal of
Volume 16, Issue 11, Nov 1980 Page(s):1207 - 1207
[AbstractPlus](#) | Full Text: [PDF](#)(440 KB) IEEE JNL
24. **Laser induced atomic-molecular reaction of the rare-earth ytterbium and metals with HCl molecules**
Karlova, N.; Krynetsky, B.; Mishin, V.; Prokhorov, A.; Stelmakh, O.;
Quantum Electronics, IEEE Journal of
Volume 17, Issue 12, Part 1, Dec 1981 Page(s):2583 - 2583
[AbstractPlus](#) | Full Text: [PDF](#)(432 KB) IEEE JNL
25. **Fast plasma mixing--A new excitation method for CW gas laser**
Schaefer, G.;

Quantum Electronics, IEEE Journal of
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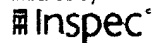
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